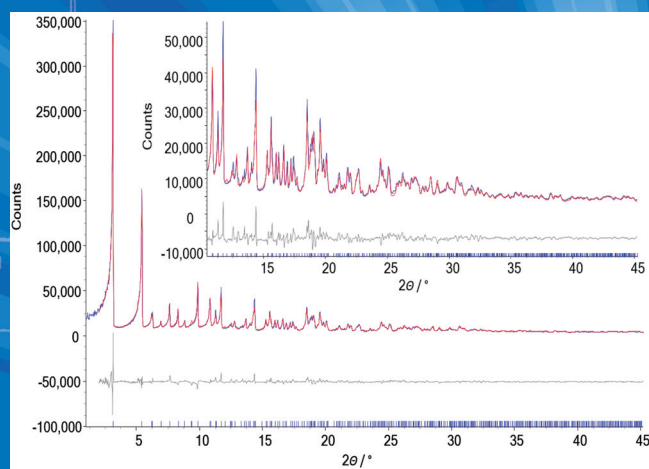
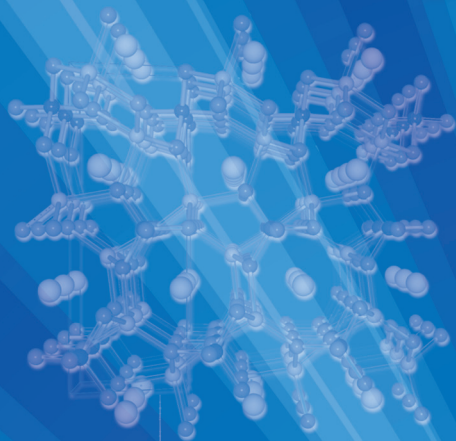
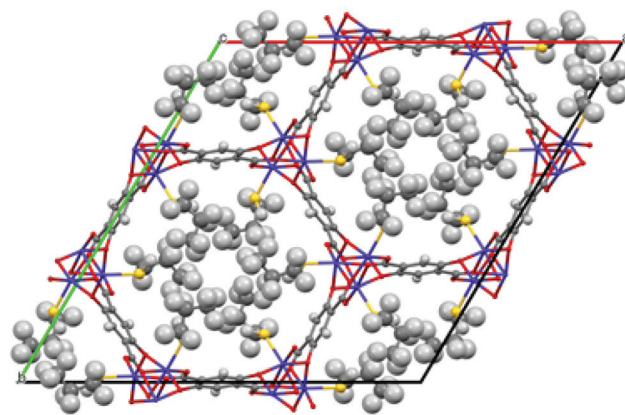


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MoK_{α1} PXRD pattern of MOF Co₂(dobdc) appended with propanethiol



Appended propanethiol molecules within the Co₂(dobdc) framework

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Powder Diffraction

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On the Cover: The invited manuscript in this issue of *Powder Diffraction* entitled "Crystal Structure of 1-propanethiol-Co₂(dobdc) from Laboratory X-ray Powder Diffraction Data" by Lefton, Pekar, Sethio, Kraka and Runcevski demonstrates the potential of PXRD and particularly the capabilities of combined Rietveld refinement with soft restraints. The left cover figure shows the high-resolution data collected using MoK_{α1} radiation. The right cover figure shows the MOF framework (lines) and the appended propanethiol guest molecules (spheres) within the pores of the metal-organic framework (MOF) Co₂(dobdc).

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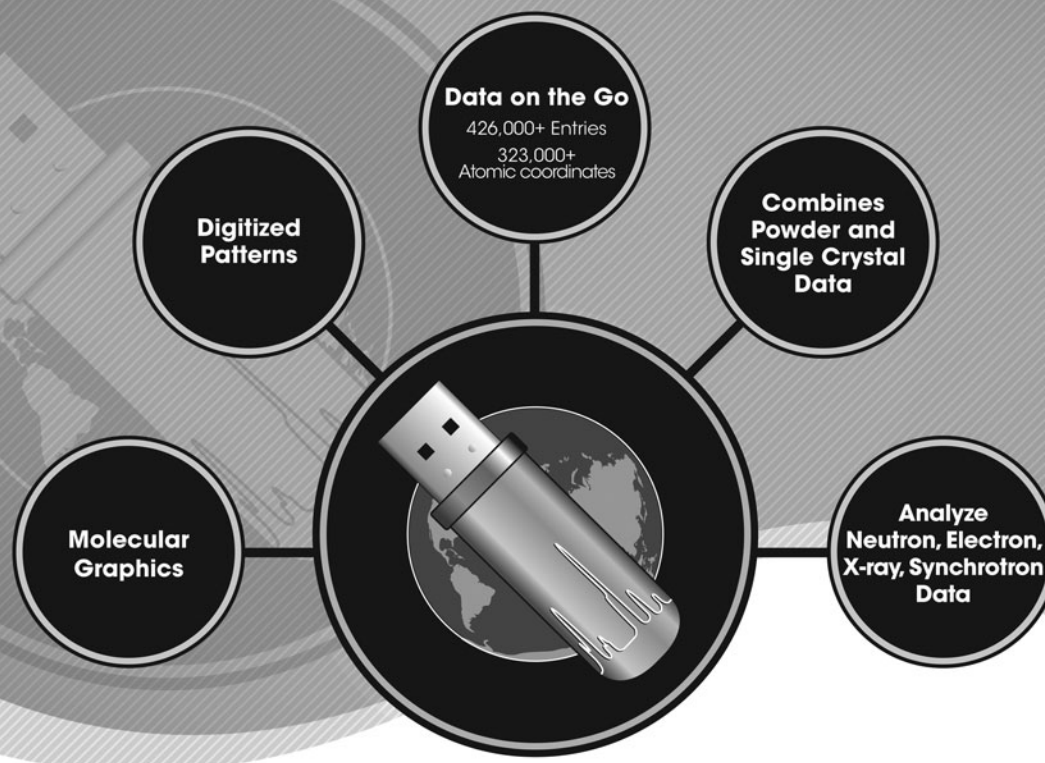
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